

NCP345

Over Voltage Protection IC

The NCP345 over-voltage protection circuit (OVP) protects sensitive electronic circuitry from over-voltage transients and power supply faults when used in conjunction with an external P-channel FET. The device is designed to sense an over-voltage condition and quickly disconnect the input voltage supply from the load before any damage can occur. The OVP consists of a precise voltage reference, a comparator with hysteresis, control logic, and a MOSFET gate driver. The OVP is designed on a robust BiCMOS process and is intended to withstand voltage transients up to 30 V.

The device is optimized for applications that have an external AC/DC adapter or car accessory charger to power the product and/or recharge the internal batteries. The nominal over-voltage threshold is 6.85 V so it is suitable for single cell Li-Ion applications as well as 3/4 cell NiCD/NiMH applications.

Features

- Over-Voltage Turn-Off Time of less than 1.0 μ sec
- Accurate Voltage Threshold of 6.85 V (nominal)
- Under-Voltage Lockout Protection
- CNTRL Input Compatible with 1.8 V Logic Levels

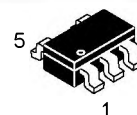
Typical Applications

- Cellular Phones
- Digital Cameras
- Portable Computers and PDAs
- Portable CD and other Consumer Electronics



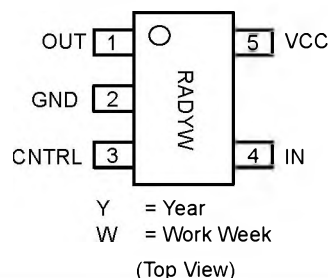
ON Semiconductor™

<http://onsemi.com>



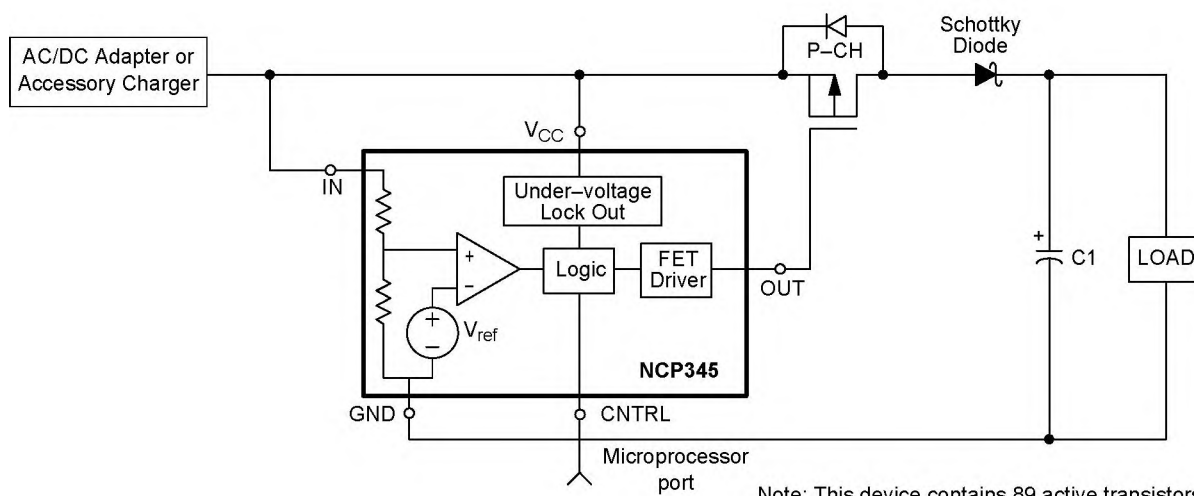
THIN SOT23-5
SN SUFFIX
CASE 483

PIN CONNECTIONS & MARKING DIAGRAM



ORDERING INFORMATION

Device	Package	Shipping
NCP345SNT1	Thin SOT23-5	3000 / 7" Reel



Note: This device contains 89 active transistors

Figure 1. Simplified Application Diagram

NCP345

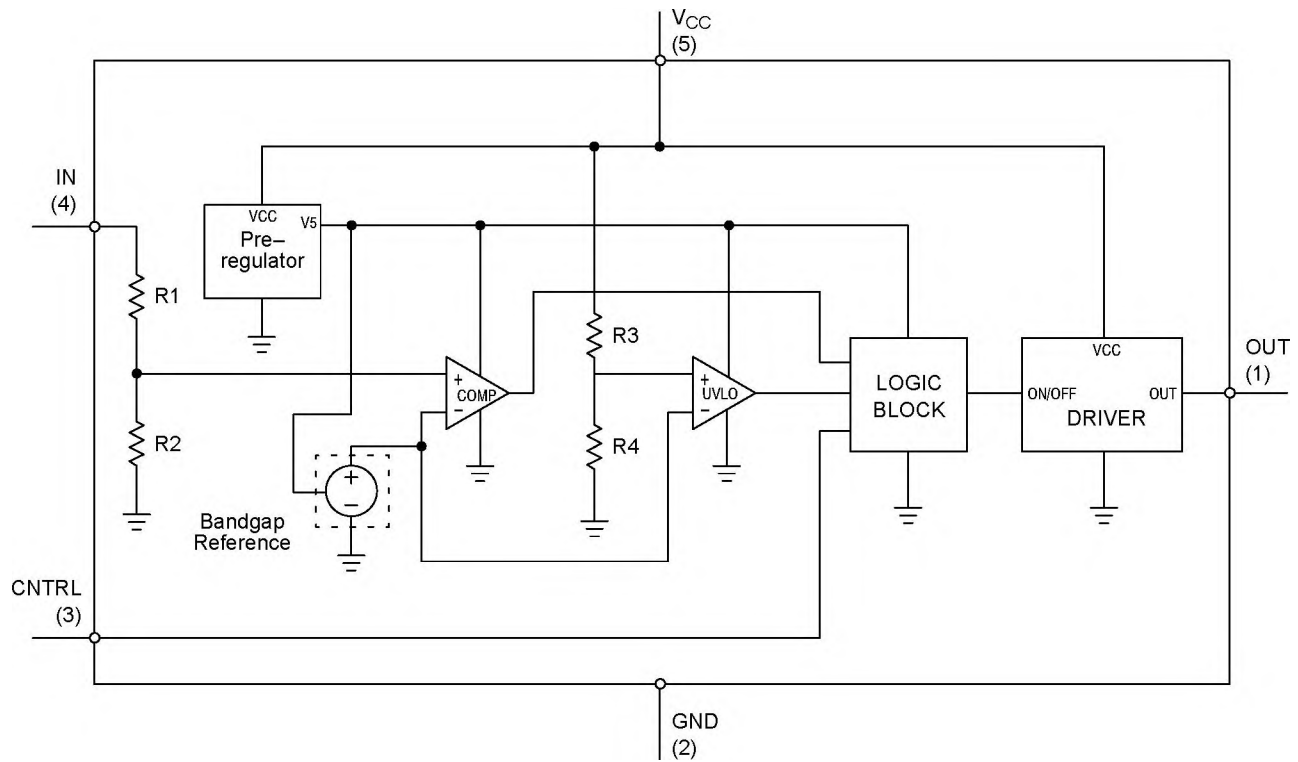


Figure 2. Detailed Block Diagram

PIN FUNCTION DESCRIPTIONS

Pin #	Symbol	Pin Description
1	OUT	This signal drives the gate of a P-channel MOSFET. It is controlled by the voltage level on IN or the logic state of the CNTRL input. When an overvoltage event is detected, the OUT pin is driven to within 1.0 V of V_{CC} in less than 1.0 μ sec provided that gate and stray capacitance is less than 12 nF.
2	GND	Circuit Ground
3	CNTRL	This logic signal is used to control the state of OUT and turn-on/off the P-channel MOSFET. A logic High results in the OUT signal being driven to within 1.0 V of V_{CC} which disconnects the FET. If this pin is not used, the input should be connected to ground.
4	IN	This pin senses an external voltage point. If the voltage on this input rises above the overvoltage threshold (V_{TH}), the OUT pin will be driven to within 1.0 V of V_{CC} , thus disconnecting the FET. The nominal threshold level is 6.85 V and this threshold level can be increased with the addition of an external resistor between IN and V_{CC} .
5	VCC	Positive Voltage supply. If V_{CC} falls below 2.8 V (nom), the OUT pin will be driven to within 1.0 V of V_{CC} , thus disconnecting the P-channel FET.

TRUTH TABLE

IN	CNTRL	OUT
$<V_{th}$	L	GND
$<V_{th}$	H	V_{CC}
$>V_{th}$	L	V_{CC}
$>V_{th}$	H	V_{CC}

NCP345

ABSOLUTE MAXIMUM RATINGS* (T_A = 25°C unless otherwise noted.)

Rating	Pin	Symbol	Min	Max	Unit
OUT voltage to GND	1	V _O	−0.3	30	V
Input and CNTRL pin voltage to GND	4 3	V _{input} V _{CNTRL}	−0.3 −0.3	30 13	V
V _{CC} Maximum Range	5	V _{CC(max)}	−0.3	30	V
Maximum Power Dissipation at T _A = 85°C	—	P _D	—	0.216	W
Thermal Resistance Junction to Air	—	R _{θJA}	—	300	°C/W
Junction Temperature	—	T _J	—	150	°C
Operating Ambient Temperature	—	T _A	−40	85	°C
V _{CNTRL} Operating Voltage	3	—	0	5.0	V
Storage Temperature Range	—	T _{stg}	−65	150	°C
ESD performance (HBM)†	all	—	2.5	—	kV

* Maximum Ratings are those values beyond which damage to the device may occur.

† Human body model (HBM): MIL STD 883C Method 3015–7, (R = 1500 ohms, C = 100 pf, F = 3 pulses delay 1 s).

ELECTRICAL CHARACTERISTICS

(For typical values T_A = 25°C, for min/max values T_A = −40°C to +85°C, V_{CC} = 6.0 V, unless otherwise noted.)

Characteristic	Symbol	Pin	Min	Typ	Max	Unit
V _{CC} Operating Voltage Range	V _{CC(opt)}	5	3.0	4.8	25	V
Supply Current (I _{CC} + I _{input} ; V _{CC} = 6.0 V Steady State)	—	4,5	—	0.75	1.0	mA
Input Threshold (V _{input} connected to V _{CC} ; V _{input} increasing)	V _{Th}	4	6.70	6.85	7.05	V
Input Hysteresis (V _{input} connected to V _{CC} ; V _{input} decreasing)	V _{Hyst}	4	50	100	200	mV
Input Impedance (Input = V _{Th})	R _{in}	4	70	150	—	kΩ
CNTRL Voltage High	V _{ih}	3	1.5	—	—	V
CNTRL Voltage Low	V _{il}	3	—	—	0.5	V
CNTRL Current High (V _{ih} = 5.0 V)	I _{ih}	3	—	95	200	μA
CNTRL Current Low (V _{il} = 0.5 V)	I _{il}	3	—	10	20	μA
Under Voltage Lockout (V _{CC} decreasing)	V _{Lock}	3	2.5	2.8	3.0	V
Output Sink Current (V _{CC} < V _{Th} , V _{OUT} = 1.0 V)	I _{Sink}	1	10	33	50	μA
Output Voltage High (V _{CC} = V _{in} = 8.0 V; I _{Source} = 10 mA) Output Voltage High (V _{CC} = V _{in} = 8.0 V; I _{Source} = 0.25 mA) Output Voltage High (V _{CC} = V _{in} = 8.0 V; I _{Source} = 0 mA)	V _{oh}	1	V _{CC} −1.0 V _{CC} −0.25 V _{CC} −0.1	— — —	— — —	V
Output Voltage Low (Input < 6.5 V; I _{Sink} = 0 mA; V _{CC} = 6.0 V, CNTRL = 0 V)	V _{ol}	1	—	—	0.1	V
Turn ON Delay – Input (V _{input} connected to V _{CC} ; V _{input} step down signal from 8.0 to 6.0 V; measured to 50% point of OUT)*	T _{ON IN}	1	—	—	10	μsec
Turn OFF Delay – Input (V _{input} connected to V _{CC} ; V _{input} step up signal from 6.0 to 8.0 V; C _L = 12 nF Output > V _{CC} −1.0 V)	T _{OFF IN}	1	—	0.5	1.0	μsec
Turn ON Delay – CNTRL (CNTRL step down signal from 2.0 to 0.5 V; measured to 50% point of OUT)*	T _{ON CT}	1	—	—	10	μsec
Turn OFF Delay – CNTRL (CNTRL step up signal from 0.5 to 2.0 V; C _L = 12 nF Output > V _{CC} −1.0 V)	T _{OFF CT}	1	—	1.0	2.0	μsec

*Turn ON Delay is guaranteed by design.

NCP345

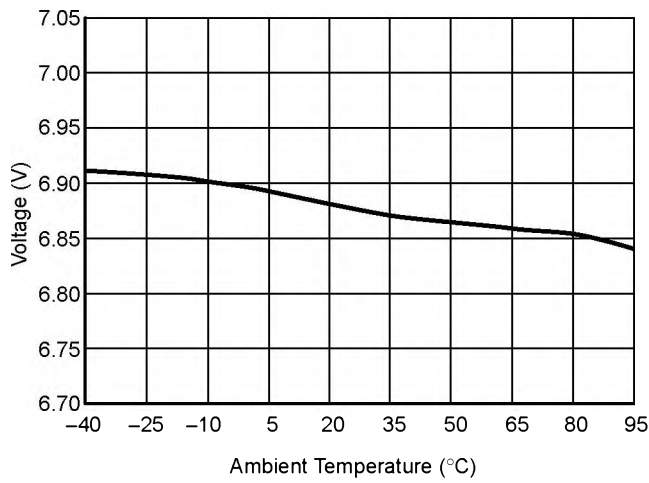


Figure 3. Typical V_{th} Threshold Variation vs. Temperature

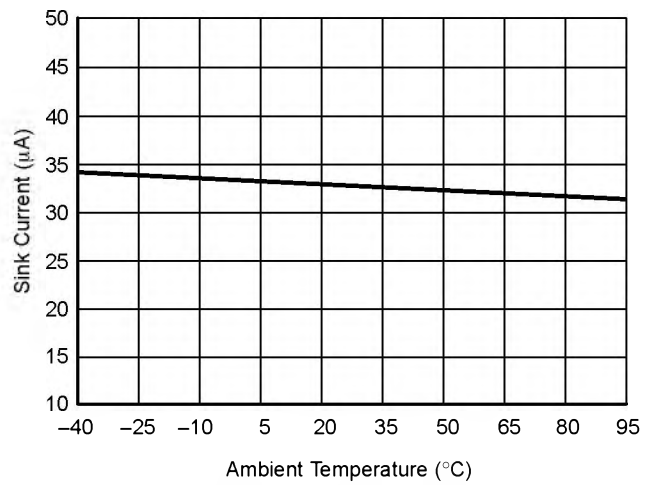


Figure 4. Typical OUT Sink Current vs. Temperature
 $V_{in} < V_{th}$, $V_{out} = 1\text{ V}$

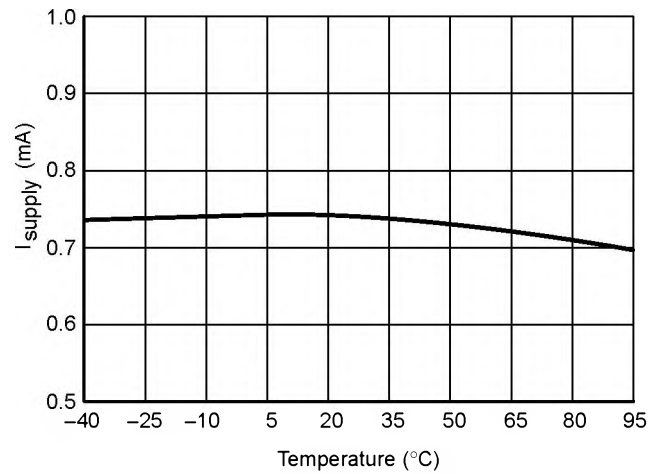


Figure 5. Typical Supply Current vs. Temperature
 $I_{cc} + I_{in}$, $V_{CC} = 6\text{ V}$

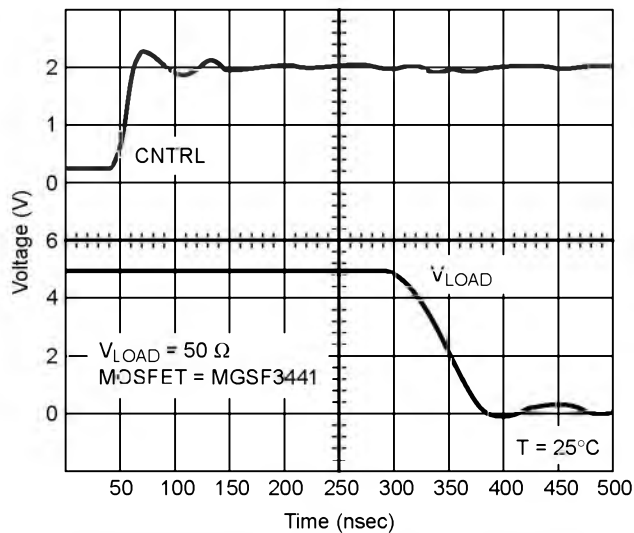


Figure 6. Typical Turn-off Time CNTRL to V_{LOAD}

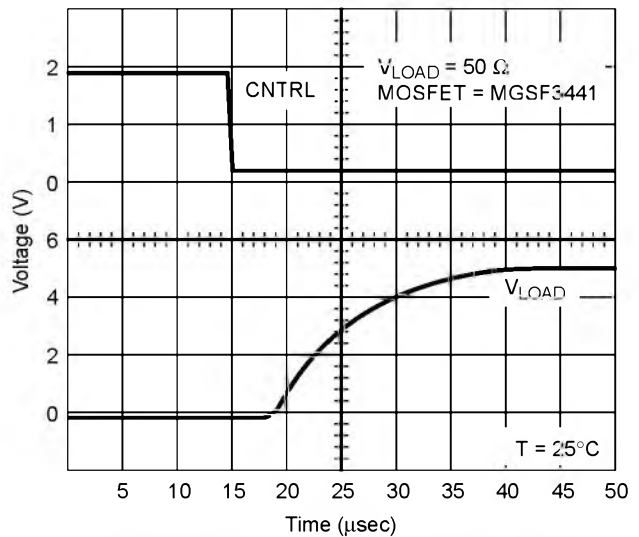


Figure 7. Typical Turn-on Time CNTRL to V_{LOAD}

APPLICATION INFORMATION

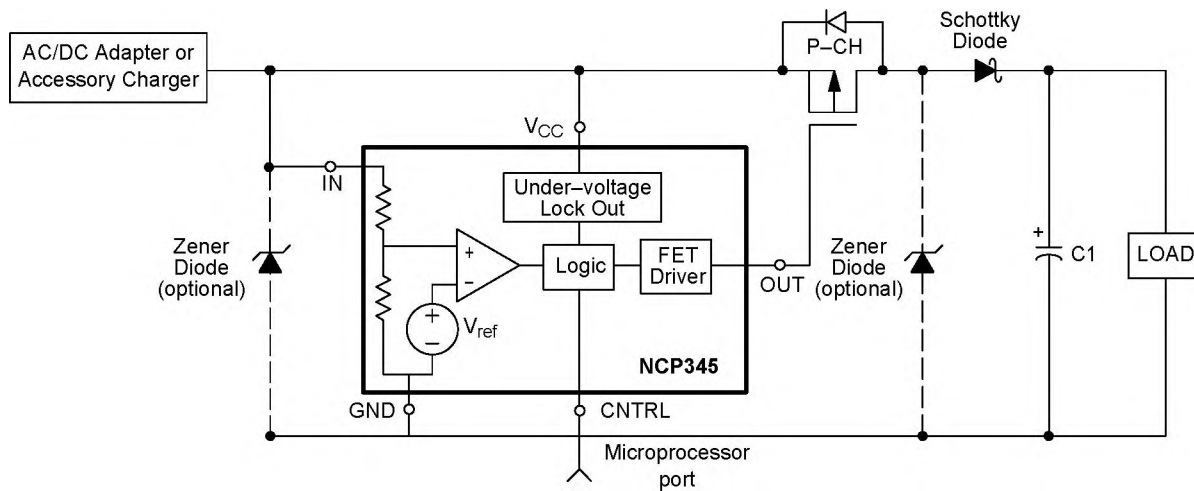


Figure 8.

Introduction

In many electronic products, an external AC/DC wall adapter is used to convert the AC line voltage into a regulated DC voltage or a current limited source. Line surges or faults in the adapter may result in over-voltage events that can damage sensitive electronic components within the product. This is becoming more critical as the operating voltages of many integrated circuits have been lowered due to advances in sub-micron silicon lithography. In addition, portable products with removable battery packs pose special problems since the pack can be removed at any time. If the user removes a pack in the middle of charging, a large transient voltage spike can occur which can damage the product. Finally, damage can result if the user plugs in the wrong adapter into the charging jack. The challenge of the product designer is to improve the robustness of the design and avoid situations where the product can be damaged due to un-expected, but unfortunately, likely events that will occur as the product is used.

Circuit Overview

To address these problems, the protection system above has been developed consisting of the NCP345 Over Voltage Protection IC and a P-channel MOSFET switch such as the MGSF3441. The NCP345 monitors the input voltage and will not turn on the MOSFET unless the input voltage is within a safe operating window that has an upper limit of 7.05 V. A zener diode can be placed in parallel to the load to provide for secondary protection during the brief time that it takes for the NCP345 to detect the over-voltage fault and disconnect the MOSFET. The decision to use this secondary diode is a function of the charging currents expected, load capacitance across the battery, and the desired protection

voltage by analyzing the dV/dT rise that occurs during the brief time it takes to turn-off the MOSFET. For battery powered applications, a low-forward voltage Schottky diode such as the MBRM120LT3 can be placed in series with the MOSFET to block the body diode of the MOSFET and prevent shorting the battery out if the input is accidentally shorted to ground. This provides additional voltage margin at the load since there is a small forward drop across this diode that reduces the voltage at the load.

When the protection circuit turns off the MOSFET, there can be a sudden rise in the input voltage of the device. This transient can be quite large depending on the impedance of the supply and the current being drawn from the supply at the time of an over-voltage event. This inductive spike can be clamped with a zener diode from IN to ground. This diode breakdown voltage should be well above the worst case supply voltage provided from the AC/DC adapter or Cigarette Lighter Adapter (CLA), since the zener is only intended to clamp the transient. The NCP345 is designed so that the IN and V_{CC} pin can safely protect up to 25 V and withstand transients to 30 V. Since these spikes can be very narrow in duration, it is important to use a high bandwidth probe and oscilloscope when prototyping the product to verify the operation of the circuit under all the transient conditions. A similar problem can result due to contact bounce as the DC source is plugged into the product.

For portable products it is normal to have a capacitor to ground in parallel with the battery. If the product has a battery pack that is easily removable during charging, this scenario should be analyzed. Under that situation, the charging current will go into the capacitor and the voltage may rise rapidly depending on the capacitor value, the charging current and the power supply response time.

Normal Operation

Figure 1 illustrates a typical configuration. The external adapter provides power to the protection system so the circuitry is only active when the adapter is connected. The OVP monitors the voltage from the charger and if the voltage exceeds a nominal voltage of 6.85 V, the OUT signal drives the gate of the MOSFET to within 1.0 V of VCC, thus turning off the FET and disconnecting the source from the load. The nominal time it takes to drive the gate to this state is 400 nsec (1.0 usec maximum for gate capacitance of < 12 nF). Typical turn off performance using the CNTRL input can be seen in Figure 6. The CNTRL input can also be used to interrupt charging and allow the microcontroller to measure the cell voltage under a normal condition to get a more accurate measure of the battery voltage. Once the over voltage is removed, the NCP345 will turn on the MOSFET. The turn on circuitry is designed to turn on the MOSFET more gradually to limit the in-rush current. Typical turn-on

performance is illustrated using the MGSF3441 in Figure 7. This characteristic is a function of the threshold of the MOSFET and will vary depending on the device characteristics such as the gate capacitance.

The OVP has an under voltage lockout (UVLO) circuit which disables the gate driver circuit until the UVLO senses that the VCC voltage is above 2.6 V. Once the UVLO has released the gate driver circuit, the OUT signal will stay high until the voltage on the IN is sensed. If the input voltage to IN is less than 6.85 V nominal, then the OUT signal will be driven LOW and the FET will be turned on so the source can be connected to the load.

There are three events that will cause the OVP to drive the gate of the FET to a HIGH state.

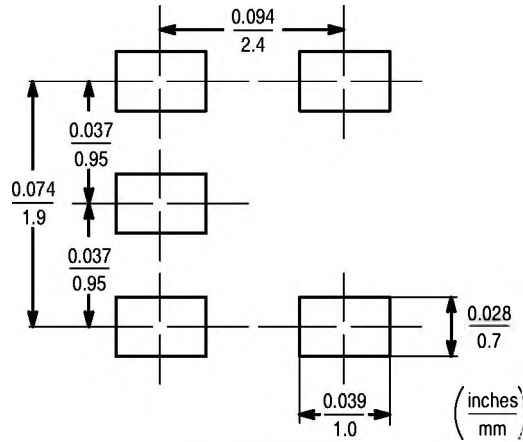
- Voltage on VCC falls below the UVLO threshold
- Voltage on IN rises above 6.85 V (nominal)
- CNTRL input is driven to a logic High

INFORMATION FOR USING THE THIN SOT23-5 SURFACE MOUNT PACKAGE

MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to insure proper solder connection

interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



THIN SOT23-5

THIN SOT23-5 POWER DISSIPATION

The power dissipation of the Thin SOT23-5 is a function of the pad size. This can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by $T_{J(max)}$, the maximum rated junction temperature of the die, $R_{\theta JA}$, the thermal resistance from the device junction to ambient, and the operating temperature, T_A . Using the values provided on the data sheet for the Thin SOT23-5 package, P_D can be calculated as follows:

$$P_D = \frac{T_{J(max)} - T_A}{R_{\theta JA}}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature T_A of 25°C, one can calculate the power dissipation of the device which in this case is 400 milliwatts.

$$P_D = \frac{150^\circ\text{C} - 25^\circ\text{C}}{300^\circ\text{C/W}} = 417 \text{ milliwatts}$$

The 300°C/W for the Thin SOT23-5 package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 417 milliwatts.

SOLDERING PRECAUTIONS

The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

- Always preheat the device.
- The delta temperature between the preheat and soldering should be 100°C or less.*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.
- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes. Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.

*Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.